

ABSTRACT

It is known that reforming implantable defibrillator capacitors at least partially restores and preserves their charging efficiency. An industry-recognized standard is to reform implantable capacitors by pulse discharging the connected electrochemical cell about once every three months throughout the useful life of the medical device. A Li/SVO cell typically powers such devices. The present invention relates to methodologies for accurately determining the precise boundaries of voltage delay and irreversible Rdc growth region in the about 25% to 70% DOD region so that more frequent pulse discharging for the purpose of cell reform is confined to the limits of the region. At the same time, the connected capacitors in the cardiac defibrillator are reformed to maintain them at their rated breakdown voltages.